

Near Infrared Polariscope

Fullauto StrainEye

LSM-9001NIR

- ✓ Evaluate strain distribution of Si, SiC, GaN and glass wafers
- ✓ Evaluation of 50 x 50mm area in 1 minute by plane distribution
- ✓ Evaluate strain distribution of colored glass and acrylic resin

Enables quality control of silicon wafer

■ This is a fully automatic polarimeter for low phase difference products such as semiconductor wafers.

We'll evaluate your samples anytime!





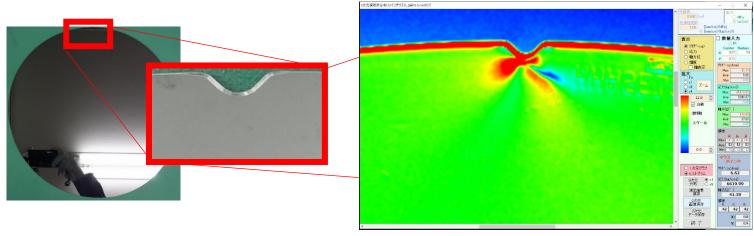
Target products

You can evaluate resin product like these colors!

- Si / SiC / GaN / Glass wafer
- Transparent/colored resin products
- Crystallized quartz / Quartz / Optical crystals

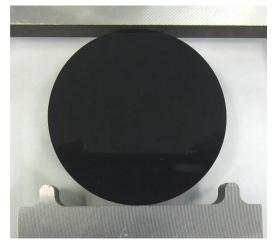


■ Evaluation Examples Silicon wafer / Colored acrylic resin molded

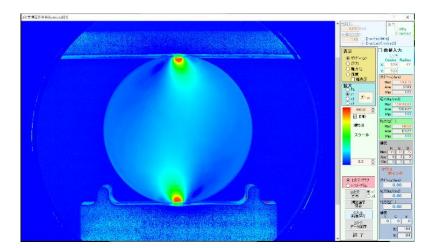


Silicon wafer Around the notch

Strain distribution (Residual stress in the grinding process)



Black acrylic resin disc under compressive load



Strain distribution

Specification

Specification	Near Infrared Polariscope LSM-9001NIR
Display items	Retardation (nm), Stress (MPa)
Measurement range	0∼150nm
Measurement area size	Approx. 50 × 50mm
Inspection method	NIR Rotating Analyzer Method
Size / Weight(body)	W300 × D353 × H540mm / 22kg

We offer sample measurement service.
There are a variety of polariscopes besides LSM-9001NIR.
Please feel free to contact us via "CONTACT US".



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